

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/730,173 | Applicant(s)/Patent Under Reexamination SPOHN ET AL. | |
| | Examiner Philip H Leung | Art Unit 3742 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-2,839,651 | 06-1958 | ERICKSON LEWIS C | 219/649 |
| | B | US-3,883,386 | 05-1975 | Garbini et al. | 219/675 |
| | C | US-6,045,648 | 04-2000 | Palmgren et al. | 219/634 |
| | D | US-6,048,599 | 04-2000 | Chu et al. | 219/634 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------|----------------|
| | N | 09-215605 | 08-1997 | JP | Uemura | ----- |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.